

A Comparison of Quality Measures for Electron Backscatter Diffraction Patterns

Stuart I. Wright and Matthew M. Nowell, EDAX/TSL, 392 E 12300 S, Draper, UT 84020 USA

The image quality of an electron backscatter diffraction (EBSD) pattern is a function of the state of the crystal lattice within the diffracting volume. Thus, maps constructed using pattern quality measures obtained from automated EBSD scans may provide phase contrast, orientation contrast and an indication of local strain. This presentation will explore some proposed measures of pattern quality and compare results over a matrix of materials to investigate the sensitivity of these measures to different